

**IN THE U. S. PATENT AND TRADEMARK OFFICE**

In re application of

Iiro HIETANEN et al.

Conf. 6321

Application No. 10/533,645

Group 2877

Filed: January 13, 2006

Examiner Rebecca Slomski

Title: SYNCHRONOUS OPTICAL MEASUREMENT  
AND INSPECTION METHOD AND MEANS

**AMENDMENT**

Assistant Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

April 22, 2009

Sir:

In response to the non-final Office Action mailed January 22, 2009, please amend the above-identified application as follows:

**Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.

**Remarks** begin on page 12 of this paper.